OPEN Publisher Correction: Resolving the positions of defects in superconducting quantum bits

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Published online: 10 March 2020

Correction to: *Scientific Reports* <https://doi.org/10.1038/s41598-020-59749-y>, published online 20 February 2020

This Article contains an error in the Figure 3 legend and the second paragraph of the Results.

“The horizontal violet line through (b,c) provides graphical solutions of Eq. 2 for possible positions of an exemplary defect (black dots), of which those requiring nonphysically large electric dipole moments >10 Debye $\approx 2e$ are discarded (red points).”

should read:

“The horizontal violet line through (b,c) provides graphical solutions of Eq. 2 for possible positions of an exemplary defect (black dots), of which those requiring nonphysically large electric dipole moments >10 Debye $\approx 2e\text{\AA}$ are discarded (red points).”

“Therefore, we discard in our analysis all solutions that imply dipole moments $p_{\parallel} > 10$ Debye $\approx 2e$ which is a maximum imaginable number in solids²⁴.”

should read:

“Therefore, we discard in our analysis all solutions that imply dipole moments $p_{\parallel} > 10$ Debye $\approx 2e\text{\AA}$ which is a maximum imaginable number in solids²⁴.”

Furthermore, this Article contains an error in the conclusions.

“The demonstrated technique to determine the position of defects on the surface of a quantum circuit provides a viable tool to verify the material quality and to optimize micro-fabrication steps.”

should read:

“The demonstrated technique to determine the position of defects on the surface of a quantum circuit provides a viable tool to verify the material quality and to optimize nano-fabrication steps.”

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